



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADE MARK OFFICE		ATTY DOCKET NO. 198249US2CONT		SERIAL NO. 09/689,696	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Masako NUKAGA, et al.			
				FILING DATE October 13, 2000		GROUP 2681	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>ST</i>	AA	4,236,125	11/25/80	N. BERNARD, et al.	<i>333</i>	<i>1.1</i>	
<i>ST</i>	AB	3,563,898	02/16/71	Y. NEICHI, et al.			
	AC						
	AD						
	AE						
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	AI						
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	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>ST</i>	AO	1 321 511	06/27/73	GREAT BRITAIN			
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>ST</i>	AW	Y.- S. WU, et al., IEEE Transactions on Microwave Theory and Techniques, vol. MTT-24, no. 2, pages 69-77, XP-002229537, "A STUDY OF NONLINEARITIES AND INTERMODULATION CHARACTERISTICS OF 3-PORT DISTRIBUTED CIRCULATORS", February 1976					
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>Steph E. J.</i>				Date Considered <i>9/14/04</i>			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. <b>198249US-2 CONT</b>		SERIAL NO. <b>NEW APPLICATION</b>	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT <b>MASAKO NUKAGA ET AL</b>			
				FILING DATE <b>HEREWITH</b>		GROUP	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	AA	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>ST</i>	AO	3-288406	12/18/91	JAPAN (w/English Abstract)			X
<i>ST</i>	AP	7-157313	06/20/95	JAPAN (w/English Abstract)			X
<i>ST</i>	AQ	8-288116	11/01/96	JAPAN (w/English Abstract)			X
<i>ST</i>	AR	7-51821	03/07/95	JAPAN (w/English Abstract)			X
<i>ST</i>	AS	56-10767	03/10/81	JAPAN			X
<i>ST</i>	AT	56-31288	07/20/81	JAPAN			X
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
<i>ST</i>	AW	M. Nukaga et al., "Relationship between the Magnetic Properties of YIG Ferrites and the IMD (Intermodulation Distortion) of an Isolator, Journal of the Applied Magnetics Association of Japan, Vol. 22, No. 4-2, (1998), p. 673-676					
<i>ST</i>	AX	<del>INTERNATIONAL SEARCH REPORT</del>					
Examiner <i>[Signature]</i>					Date Considered <b>9/14/04</b>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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